Search Notes



Application/Control No.	Applicant(s)/Patent under Reexamination	
10/785,402	JUNG, HEE-WON	
Examiner	Art Unit	
John L. Goodrow	1756	

SEARCHED					
Class	Subclass	Date	Examiner		
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	109.3				
	109.4				
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NO (INCLUDING SEARC	DTES H STRATEGY	·)
	DATE	EXMR
inventor name search and east	10/3/2005	1G